Application/Control N	o. Applicant(s)/Patent under Reexamination	
09/973,045	LEE, YOON-JICK	
Examiner	Art Unit .	
CongVan Tran	2617	

SEARCHED				
Class	Subclass	Date	Examiner	
455	435.1 433 456.3 456.5	5/29/2007	ст	
342	357.09	5/29/2007	СТ	
	357.1	5/29/2007	СТ	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
455	435.1 433	5/29/2007	СТ	

(INCLUDING SEAF	RCH STRATEGY)		
	DATE	EXMR	
search updated	5/29/07	Cr	
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